

Special Issue

Electromagnetic Imaging from Radio Frequency to Sub-millimeter Waves

Message from the Guest Editors

The objective of electromagnetic imaging is to retrieve information about tested structures by studying their interactions with electromagnetic waves. To make a long story short, this involves solving an inverse problem, where the measurable effect is a field-related quantity, and the cause is related to the targets' geometric and electromagnetic properties. The major benefit of using non-ionizing radiation for electromagnetic imaging is the possibility of acquiring target features and analyzing objects in a fully non-invasive and safe way. Topics of interest include, but are not limited to:

- Electromagnetic imaging
- Microwave imaging
- Millimeter-Wave imaging
- THz imaging
- Tomography
- Inverse scattering
- Inverse problems
- Subsurface imaging
- Nondestructive tests
- Through-the-Wall imaging
- Biomedical diagnostics
- Security imaging

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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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